

Search Notes

Application/Control No.

10/662,382

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

KANAI ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	700 and 778 - 781	1/31/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	1/31/2006	C.C.